

Application/Control No	Applicant(s)/Patent under Reexamination	
10/663,179	SEELIG ET AL.	
Examiner	Art Unit	
Benjamin H. Layno	3711	

	SEARCHED				
Class	Subclass	Date	Examiner		
273	269, 143R, 138.2, 138.1	7/6/2005	BHL		
463	17-20, 22				
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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